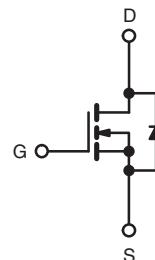


## N-Channel 500-V (D-S) Super Junction MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V) at $T_J$ max.	500	
$R_{DS(on)}$ max. at 25 °C ( $\Omega$ )	$V_{GS} = 10$ V	0.192
$Q_g$ max. (nC)	86	
$Q_{gs}$ (nC)	9	
$Q_{gd}$ (nC)	16	
Configuration	Single	

### FEATURES

- Low figure-of-merit (FOM)  $R_{on} \times Q_g$
- Low input capacitance ( $C_{iss}$ )
- Reduced switching and conduction losses
- Low gate charge ( $Q_g$ )
- Avalanche energy rated (UIS)



N-Channel MOSFET

### ABSOLUTE MAXIMUM RATINGS ( $T_C = 25$ °C, unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	$V_{DS}$	500	V
Gate-Source Voltage	$V_{GS}$	$\pm 30$	
Continuous Drain Current ( $T_J = 150$ °C)	$I_D$	18	A
		12	
Pulsed Drain Current <sup>a</sup>	$I_{DM}$	50	
Linear Derating Factor		1.25	W/°C
Single Pulse Avalanche Energy <sup>b</sup>	$E_{AS}$	186	mJ
Maximum Power Dissipation	$P_D$	206	W
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 to +150	°C
Drain-Source Voltage Slope	$dV/dt$	70	V/ns
Reverse Diode $dV/dt$ <sup>d</sup>		27	
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s	300	°C

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50$  V, starting  $T_J = 25$  °C,  $L = 28.2$  mH,  $R_g = 25$  Ω,  $I_{AS} = 3.1$  A.
- 1.6 mm from case.
- $I_{SD} \leq I_D$ ,  $dI/dt = 100$  A/μs, starting  $T_J = 25$  °C.

### THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	62	°C/W
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8	

<b>SPECIFICATIONS</b> ( $T_J = 25^\circ\text{C}$ , unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$		500	-	-	V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25^\circ\text{C}$ , $I_D = 1 \text{ mA}$		-	0.62	-	$\text{V}/^\circ\text{C}$
Gate-Source Threshold Voltage (N)	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$		2.0	-	4.0	V
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20 \text{ V}$		-	-	$\pm 100$	nA
		$V_{GS} = \pm 30 \text{ V}$		-	-	$\pm 1$	$\mu\text{A}$
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 500 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	-	10	$\mu\text{A}$
		$V_{DS} = 400 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 125^\circ\text{C}$		-	-	25	
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}$	$I_D = 9.5 \text{ A}$	-	0.192	-	$\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 30 \text{ V}$ , $I_D = 9.5 \text{ A}$		-	3.9	-	S
<b>Dynamic</b>							
Input Capacitance	$C_{iss}$	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 100 \text{ V}$ , $f = 1 \text{ MHz}$		-	1162	-	$\text{pF}$
Output Capacitance	$C_{oss}$			-	51	-	
Reverse Transfer Capacitance	$C_{rss}$			-	7	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	$C_{o(er)}$	$V_{DS} = 0 \text{ V to } 400 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	55	-	
Effective Output Capacitance, Time Related <sup>b</sup>	$C_{o(tr)}$			-	164	-	
Total Gate Charge	$Q_g$			-	33	66	$\text{nC}$
Gate-Source Charge	$Q_{gs}$	$V_{GS} = 10 \text{ V}$	$I_D = 9.5 \text{ A}$ , $V_{DS} = 400 \text{ V}$	-	8	-	
Gate-Drain Charge	$Q_{gd}$			-	14	-	
Turn-On Delay Time	$t_{d(on)}$			-	15	30	$\text{ns}$
Rise Time	$t_r$	$V_{DD} = 400 \text{ V}$ , $I_D = 12 \text{ A}$ , $V_{GS} = 10 \text{ V}$ , $R_g = 9.1 \Omega$		-	24	48	
Turn-Off Delay Time	$t_{d(off)}$		-	34	68		
Fall Time	$t_f$		-	18	36		
Gate Input Resistance	$R_g$	$f = 1 \text{ MHz}$ , open drain		-	0.85	-	$\Omega$
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_s$	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14.5	$\text{A}$
Pulsed Diode Forward Current	$I_{SM}$			-	-	28	
Diode Forward Voltage	$V_{SD}$	$T_J = 25^\circ\text{C}$ , $I_S = 9.5 \text{ A}$ , $V_{GS} = 0 \text{ V}$		-	-	1.2	V
Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ\text{C}$ , $I_F = I_S = 9.5 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_R = 25 \text{ V}$		-	265	-	ns
Reverse Recovery Charge	$Q_{rr}$			-	3.2	-	$\mu\text{C}$
Reverse Recovery Current	$I_{RRM}$			-	23	-	A

**Notes**

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .  
 b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

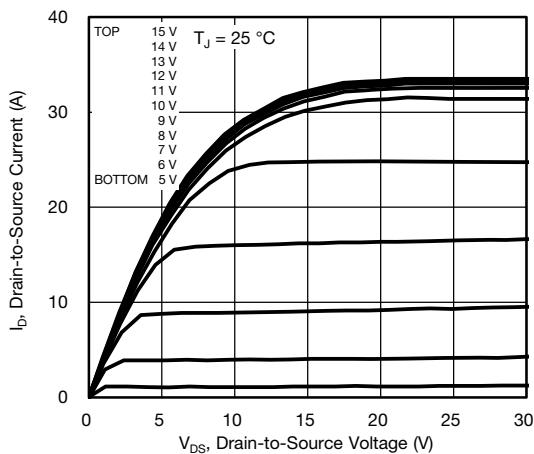
**TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics

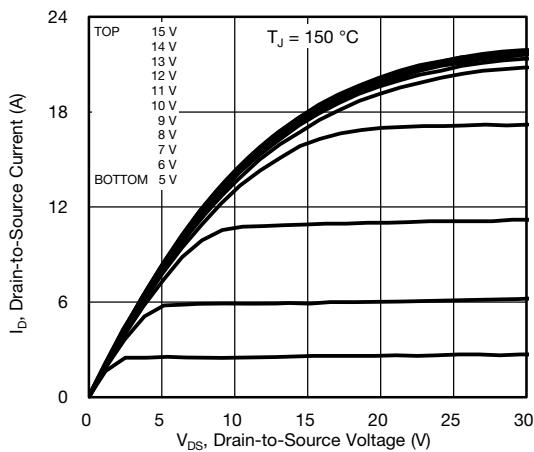


Fig. 2 - Typical Output Characteristics

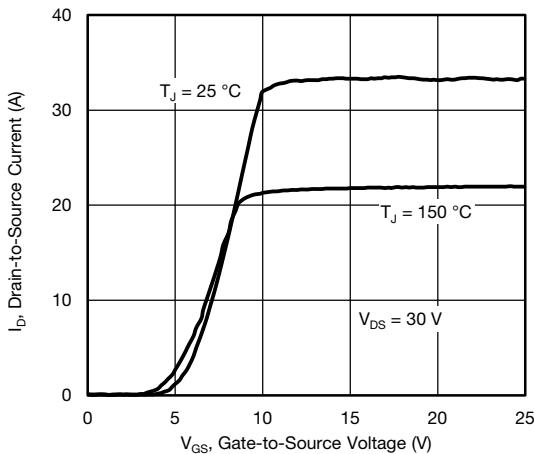


Fig. 3 - Typical Transfer Characteristics

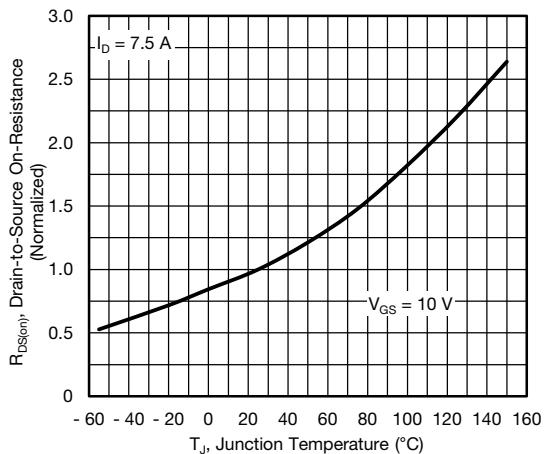


Fig. 4 - Normalized On-Resistance vs. Temperature

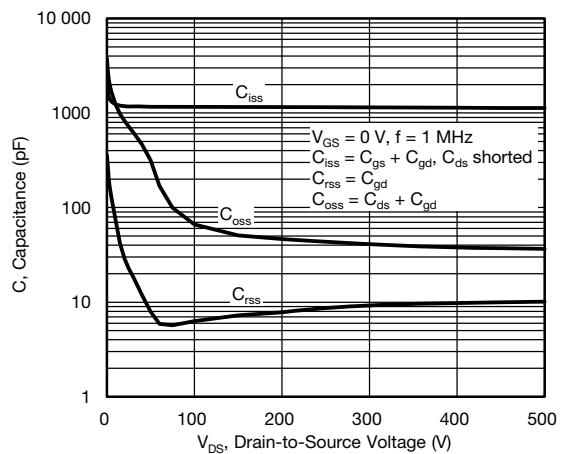
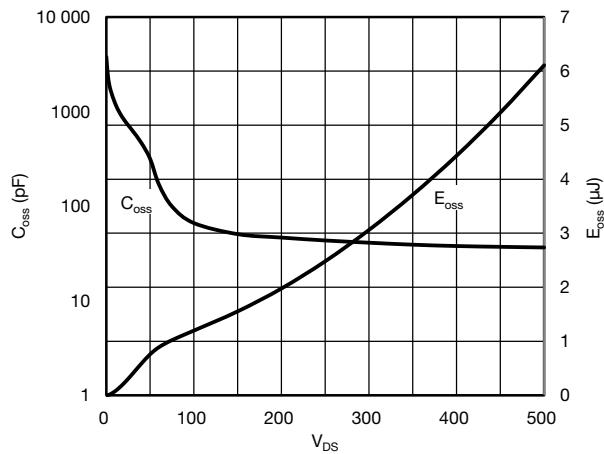


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$

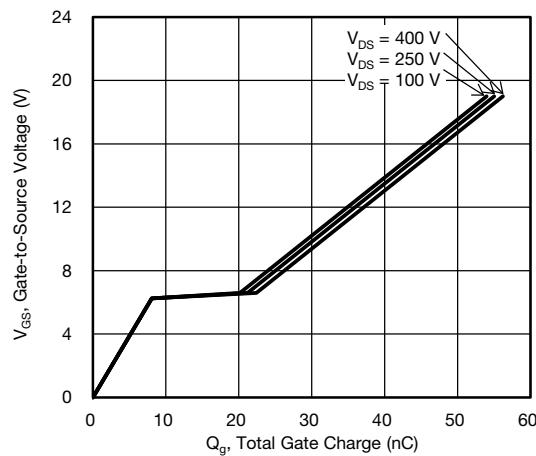


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

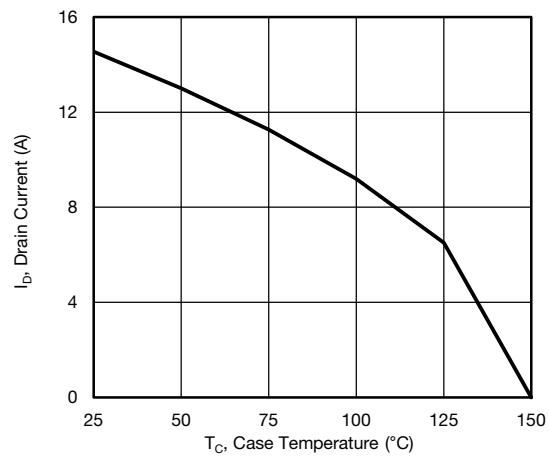


Fig. 10 - Maximum Drain Current vs. Case Temperature

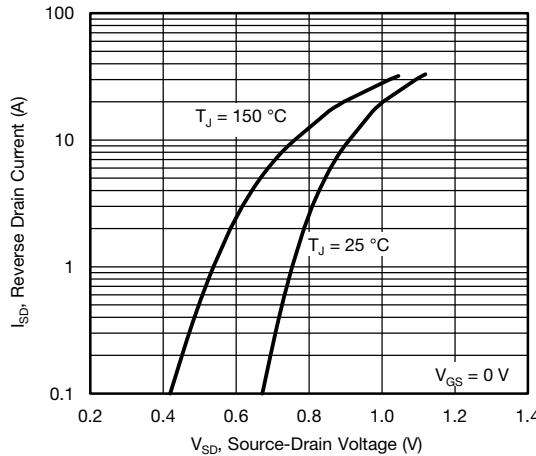


Fig. 8 - Typical Source-Drain Diode Forward Voltage

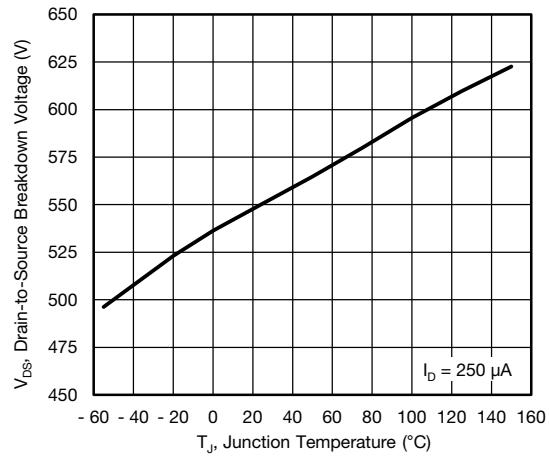


Fig. 11 - Temperature vs. Drain-to-Source Voltage

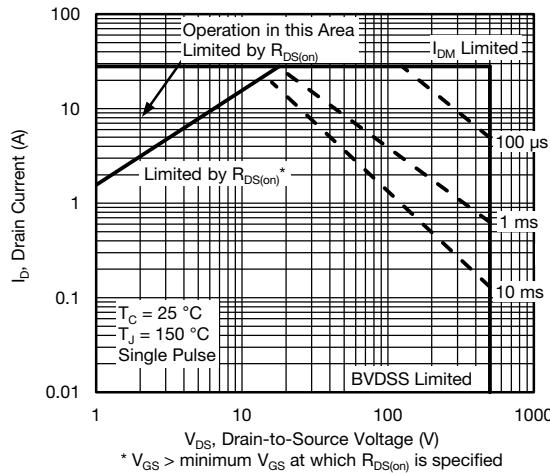


Fig. 9 - Maximum Safe Operating Area

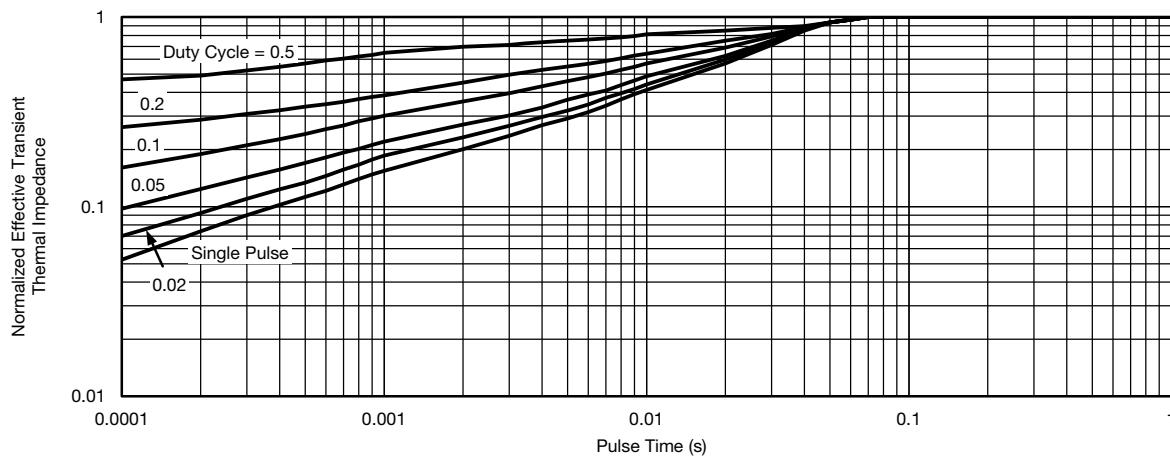


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

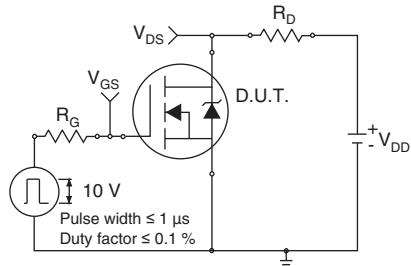


Fig. 13 - Switching Time Test Circuit

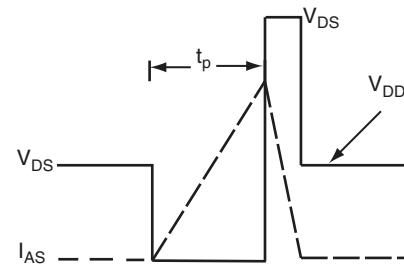


Fig. 16 - Unclamped Inductive Waveforms

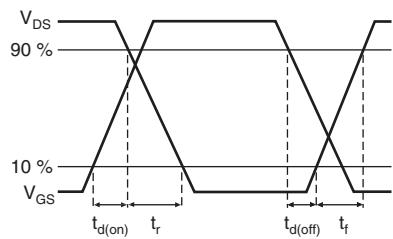


Fig. 14 - Switching Time Waveforms

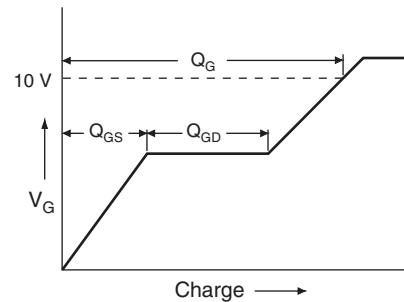


Fig. 17 - Basic Gate Charge Waveform

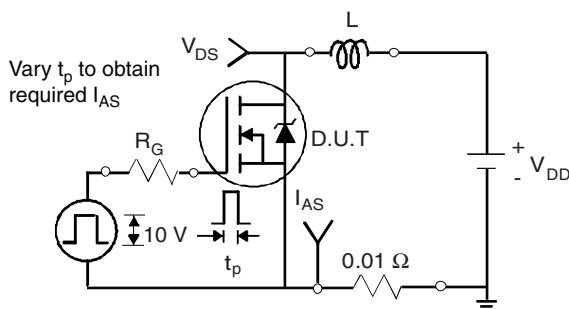


Fig. 15 - Unclamped Inductive Test Circuit

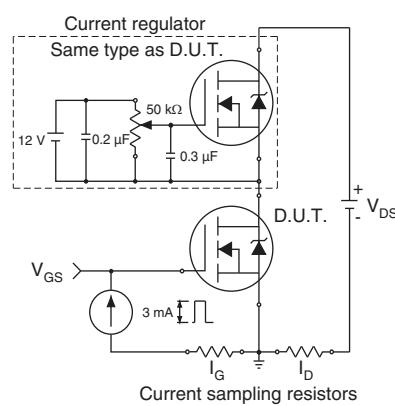
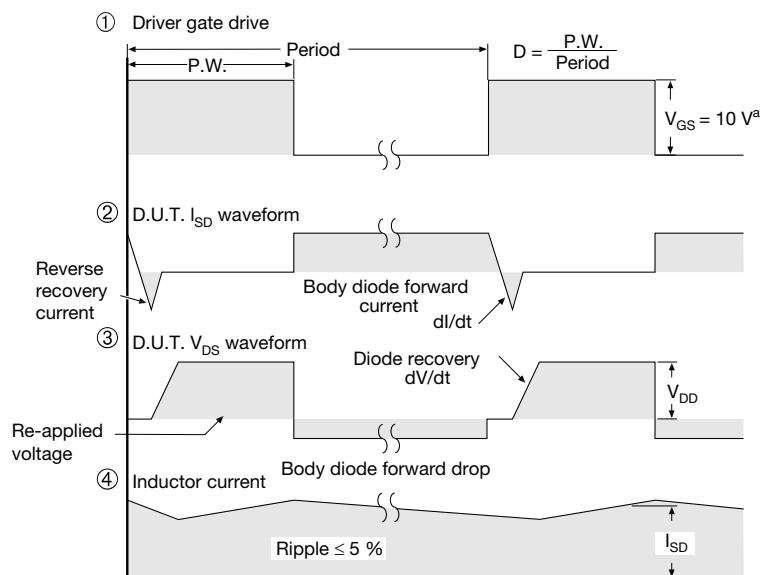
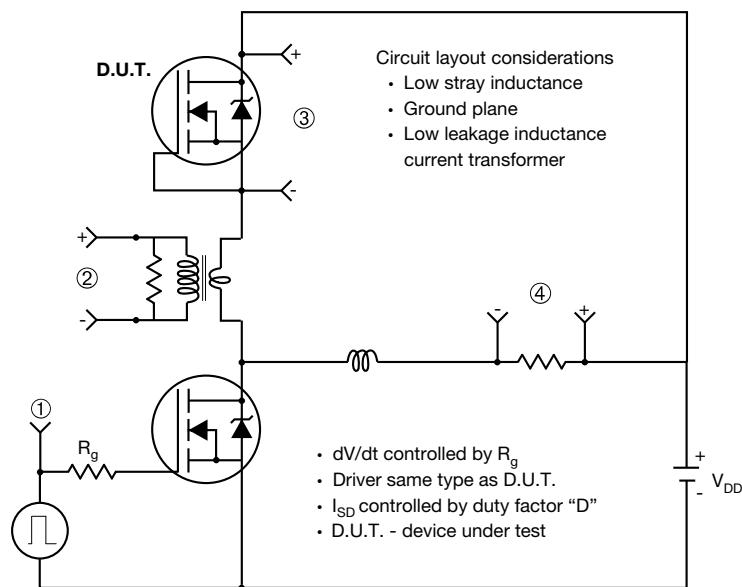


Fig. 18 - Gate Charge Test Circuit

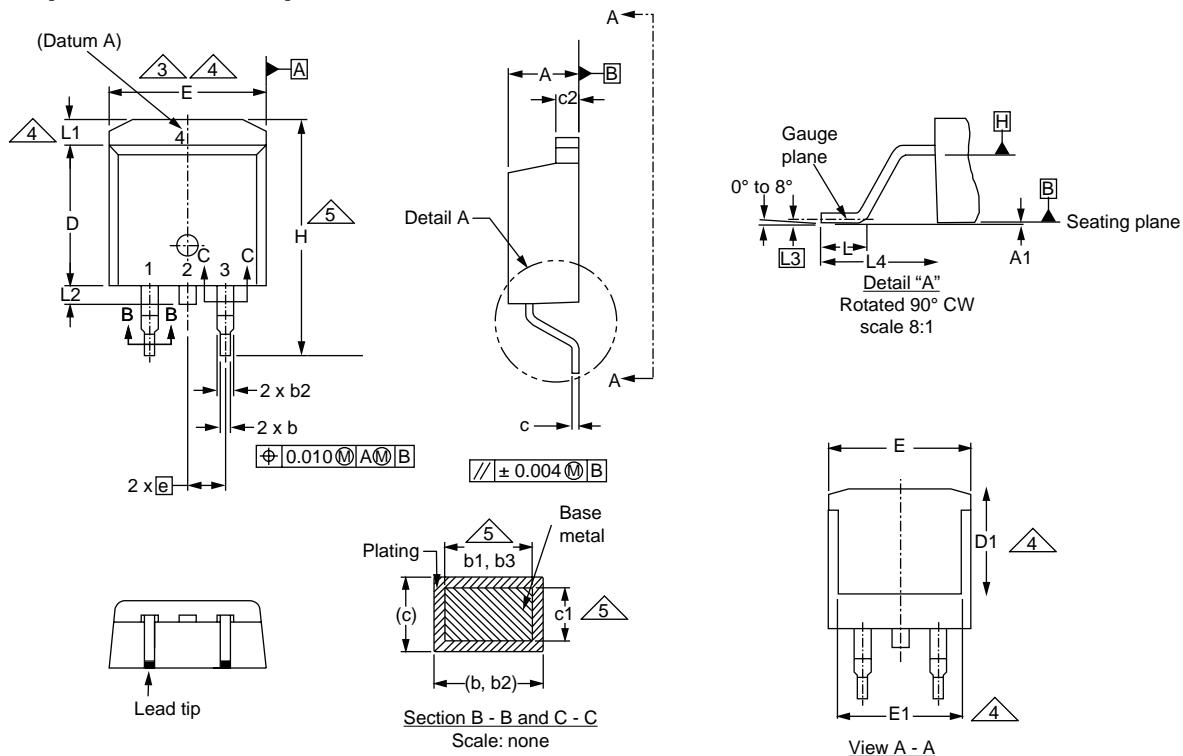
### Peak Diode Recovery dV/dt Test Circuit



**Note**

a.  $V_{GS} = 5 \text{ V}$  for logic level devices

Fig. 19 - For N-Channel

**TO-263AB (HIGH VOLTAGE)**

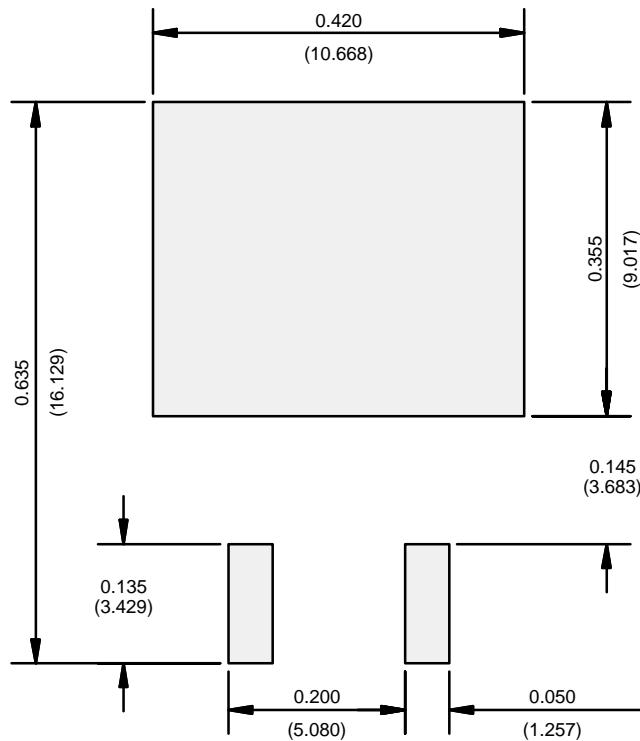
DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
c	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

ECN: S-82110-Rev. A, 15-Sep-08  
 DWG: 5970

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
e	2.54 BSC		0.100 BSC	
H	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010 BSC	
L4	4.78	5.28	0.188	0.208

**Notes**

- Dimensioning and tolerancing per ASME Y14.5M-1994.
- Dimensions are shown in millimeters (inches).
- Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- Thermal PAD contour optional within dimension E, L1, D1 and E1.
- Dimension b1 and c1 apply to base metal only.
- Datum A and B to be determined at datum plane H.
- Outline conforms to JEDEC outline to TO-263AB.

**RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead**

Recommended Minimum Pads  
Dimensions in Inches/(mm)

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